

**Search Notes**

Application/Control No.

10/753,101

Examiner

EMEM EKONG

Applicant(s)/Patent under  
Reexamination

JIN ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
330	285,51, 310,311, 289 272-273	10/12/2005	EOE
455	343,280	4/19/2006	EOE
	574,572		
	550.1,73		
	127		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
LNA and (baising or (Bias adj circuit) or bias) and (switch or switch\$3 or (switch\$3 adj circuit)) and ((replica adj circuit)	10/12/2005	eeo
east update	4/19/2006	eeo